





The Magic of **Correlation Measurements**

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- Spectral measure and estimation
- Theory of the cross spectrum
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Correlation measurements



Two separate instruments measure the same DUT. Only the DUT noise is common

noise measurements		
DUT noise, normal use	a, bc	instrument noise DUT noise
background, ideal case	a, bc = 0	instrument noise no DUT
background, real case	a, bc ≠ 0	c is the correlated instrument noise Zero DUT noise



Statistics

Boring but necessary exercises

Vocabulary of statistics

- A random process x(t) is defined through a random experiment e that associates a function x_e(t) with each outcome e.
 - The set of all the possible x_e(t) is called *ensemble*
 - The function x_e(t) is called *realization* or *sample function*.
 - The ensemble average is called mathematical expectation $\mathbb{E}\{ \}$
- A random process is said *stationary* if its statistical properties are independent of time.
 - Often we restrict the attention to some statistical properties.
 - In physics, this is the concept of repeatability.
- A random process x(t) said *ergodic* if a realization observed in time has the statistical properties of the ensemble.
 - Ergodicity makes sense only for stationary processes.
 - Often we restrict the attention to some statistical properties.
 - In physics, this is the concept of reproducibility.

Example: thermal noise of a resistor of value R

- The experiment e is the random choice of a resistor e
- The realization $x_e(t)$ is the noise waveform measured across the resistor e
- We always measure <x²>=4kTRB, so the process is stationary
- After measuring many resistors, we conclude that <x²>=4kTRB always holds. The process is ergodic.

A relevant property of random noise

A theorem states that there is no a-priori relation between PDF¹ and spectral measure

For example, white noise can originate from

- Poisson process (emission of a particle at random time)
- Random telegraph (random switch between two level)
- Thermal noise (Gaussian)

(1) PDF = Probability Density Function

Why Gaussian White Noise?

- Whenever randomness occurs at microscopic level, noise tends to be Gaussian (central-limit theorem)
- Most environmental effects are not "noise" in strict sense (often, they are more disturbing than noise)
- Colored noise types (1/f, 1/f², etc) can be whitened, analyzed, and un-whitened
- Of course, GW noise is easy to understand

Properties of Gaussian White noise with zero mean x(t) <=> X(If) = X'(If)+IX"(If)

- 1. $x(t) \iff X(if)$ are Gaussian 2. $X(if_1)$ and $X(if_2)$, $f_1 \neq f_2$
 - 1. are statistically independent,
 - 2. var{X(If₁)} = var{X(If₂)}
- 3. real and imaginary part:
 - 1. X' and X" are statistically independent
 - 2. var{X'} = var{X''} = var{X}/2
- 4. $Y = X_1 + X_2$
 - 1. Y is Gaussian
 - **2.** var{Y} = var{X₁} + var{X₂}
- **5.** $Y = X_1 \times X_2$
 - 1. is Gaussian
 - 2. var{Y} = var{X₁} var{X₂}



Properties of parametric noise x(t) <=> X(If) = X'(If)+IX"(If)

- 1. Pair x(t) <=> X(ıf)
 - 1. there is no a-priori relation between the distribution of x(t) and X(If) (theorem)
 - 2. Central limit theorem: x(t) and X(If) end up to be Gaussian
- **2.** X(If₁) and X(If₂)
 - 1. generally, statistically independent
 - 2. var{X(If₁)} ≠ var{X(If₂)} in general
- 3. Real and imaginary part, same frequency
 - 1. X' and X" can be correlated
 - 2. var{X'} ≠ var{X"} ≠ var{X}/2
- 4. Y = X₁ + X₂, zero-mean independent
 Gaussian r.v.
 var{Y} = var{X₁} + var{X₂}
- 5. If X₁ and X₂ are zero-mean independent Gaussian r.v.
 - 1. $Y = X_1 \times X_2$ is zero-mean Gaussian
 - 2. var{Y} = var{X₁} var{X₂}



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The process has N ... 2N degrees of freedom, depending on correlation between X' and X"

Children of the Gaussian distribution



Spectral measure¹ and estimation

(1) Engineers call it Power Spectral Density (PSD)

The Spectral Measure for stationary random process x(t)

$$C(\tau) = \mathbb{E}\left\{ [\mathbf{x}(t) - \mu] [\mathbf{x}(t - \tau) - \mu]^* \right\}$$
$$\mu = \mathbb{E}\{\mathbf{x}\}$$
$$S(\omega) = \mathcal{F}\{C(\tau)\} = \int_{-\infty}^{\infty} C(\tau) e^{-i\omega\tau} d\tau$$

Autocovariance Improperly referred to as the correlation and denoted with $R_{xx}(\tau)$

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Spectral measure (two-sided)

 $C(\tau) = \lim_{T \to \infty} \int_{-T/2}^{T/2} [x(t) - \mu] [x(t - \tau) - \mu]^* dt$ For ergodic process, interchation and time average process x(t) -> realization x(t)

For ergodic process, interchange

$$S(\omega) = \lim_{T \to \infty} \frac{1}{T} X_T(\omega) X_T^*(\omega) = \lim_{T \to \infty} \frac{1}{T} |X_T(\omega)|^2$$

Wiener Khinchin theorem for stationary ergodic processes

 $S^{I}(f) = 2S^{II}(\omega/2\pi), \quad f > 0$ In experiments we use the single-sided PSD

autocorrelation function

$$R_{\mathrm{xx}}(\tau) = \frac{1}{\sigma^2} \mathbb{E}\left\{ [\mathbf{x}(t) - \mu] [\mathbf{x}(t - \tau) - \mu] \right\}$$

Fourier transform

$$\mathcal{F}\{\xi\} = \int_{-\infty}^{\infty} \xi(t) \, e^{-i\omega t} dt$$

Sum of random variables

I. The sum of Gaussian distributed random variables has Gaussian PDF

The central limit theorem states that
 For large m, the PDF of the the sum of m statistically
 independent processes tends to a Gaussian distribution
 Let X = X₁+X₂+...+X_m be the sum of m processes of mean μ₁, μ₂, ...
 μ_m and variance σ₁², σ₂², ... σ_m². The process X has Gaussian PDF
 expectation E{X} = μ₁+μ₂+...+μ_m, and variance σ² = σ₁²+σ₂²+...+σ_m²

3. Similarly, the average $\langle X \rangle_m = (X_1 + X_2 + ... + X_m)/m$ has Gaussian PDF, E{X} = $(\mu_1 + \mu_2 + ... + \mu_m)/m$, and $\sigma^2 = (\sigma_1^2 + \sigma_2^2 + ... + \sigma_m^2)/m$

4. Since white noise and flicker noise arise from the sum of a large number of small-scale phenomena, they are Gaussian distributed

PDF = **Probability Density Function**

Product of independent zero-mean Gaussian-distributed random variables

 x_1 and x_2 are normal distributed with zero mean and variance σ_1^2 , σ_2^2

 $x = x_1 x_2$

x has Bessel K₀ distribution with variance $\sigma = \sigma_1^2 \sigma_2^2$

Thanks to the central limit theorem, the average <X>m = (X1+X2+...+Xm)/m of m products has

Gaussian PDF,
average E{X} = 0
variance V{X} = σ²

$$f(x) = \frac{1}{\pi\sigma} K_0 \left(-\frac{|x|}{\sigma}\right)$$
$$\mathbb{E}\{f(x)\} = 0$$
$$\mathbb{E}\{|f(x) - \mathbb{E}\{f(x)\}|^2\} = \sigma^2$$



Spectral Measure S_{xx}(f) (Power Spectral Density)

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X is white Gaussian noise

Take one frequency, S(f) -> S. Same applies to all frequencies



Normalization: in 1 Hz bandwidth var{X}= 1, and var{X'}= var{X''}= 1/2

Estimation of |S_{xx}(f)|



Running the measurement, m increases and S_{xx} shrinks => better confidence level

Cross Spectrum Theory

Getting close to the real game



Syx with correlated term (1)

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A, B = instrument background C = DUT noise channel 1 X = A + C channel 2 Y = B + C A, B, C are independent Gaussian noises Re{ } and Im{ } are independent Gaussian noises

Normalization: in 1 Hz bandwidth var{A} = var{B} = 1, var{C}= κ^2 var{A'} = var{A''} = var{B'} = var{B''} = 1/2, and var{C'} = var{C''} = $\kappa^2/2$

Cross-spectrum

$$\langle S_{yx} \rangle_m = \frac{1}{T} \langle YX^* \rangle_m = \frac{1}{T} \langle (Y' + iY'') \times (X' - iX'') \rangle_m$$



S_{yx} with correlated term $\kappa \neq 0$ (2)

All the DUT signal goes in Re{S_{yx}}, Im{S_{yx}} contains only noise



Normalization: in 1 Hz bandwidth var{A} = var{B} = 1, var{C}= κ^2 var{A'} = var{A''} = var{B'} = var{B''} = 1/2, and var{C'} = var{C''} = $\kappa^2/2$

A, B, C are independent Gaussian noises Re{ } and Im{ } are independent Gaussian noises

Estimator $\hat{\mathbf{S}} = |\langle \mathbf{S}_{yx} \rangle_m|$ The instrument default $|\langle S_{yx} \rangle_m| = \frac{1}{T} \sqrt{[\Re\{\langle YX^* \rangle_m\}]^2 + [\Im\{\langle YX^* \rangle_m\}]^2}$ $= \frac{1}{T} \sqrt{[\langle \mathscr{A} \rangle_m + \langle \mathscr{E} \rangle_m]^2 + [\langle \mathscr{B} \rangle_m]^2}.$

DUT

background Re

background Im

$\kappa \rightarrow 0$ Rayleigh distribution

$$\left\langle \mathscr{Z} \right\rangle_m = \sqrt{\left[\left\langle \mathscr{A} \right\rangle_m \right]^2 + \left[\left\langle \mathscr{B} \right\rangle_m \right]^2}$$

$$\mathbb{E}\{\langle \mathscr{Z} \rangle_m\} = \sqrt{\frac{\pi}{4m}} = \frac{0.886}{\sqrt{m}}$$
$$\mathbb{V}\{\langle \mathscr{Z} \rangle_m\} = \frac{1}{m} \left(1 - \frac{\pi}{4}\right) = \frac{0.215}{m}$$

$$\frac{\operatorname{dev}\{|\langle S_{yx}\rangle_m|\}}{\mathbb{E}\{|\langle S_{yx}\rangle_m|\}} = \sqrt{\frac{4}{\pi} - 1} = 0.523$$



Normalization: in 1 Hz bandwidth var{A} = var{B} = 1, var{C}= κ^2 var{A'} = var{A''} = var{B'} = var{B''} = 1/2, and var{C'} = var{C''} = $\kappa^2/2$

Estimator $\hat{S} = Re\{\langle S_{yx} \rangle_m\}$ Best (unbiased) estimator







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0 dB SNR requires that m=1/2κ⁴. Example κ=0.1 (DUT noise 20 dB lower than single-channel background) averaging on $5x10^3$ spectra is necessary to get SNR = 0 dB.

Normalization: in 1 Hz bandwidth var{A} = var{B} = 1, var{C}= κ^2 var{A'} = var{A''} = var{B'} = var{B''} = 1/2, and var{C'} = var{C''} = $\kappa^2/2$

Ergodicity

Let's collect a sequence of spectra



Ergodicity allows to interchange time statistics and ensemble statistics, thus the running index i of the sequence and the frequency f. The average and the deviation calculated on the frequency axis are the same as the average and the deviation of the sequence of spectra.



Example: Measurement of |Syx|



Measurement (C≠0), Syx



Running the measurement, m increases S_{xx} shrinks => better confidence level S_{yx} decreases => higher single-channel noise rejection

Applications

The real fun starts here

Applications

- Radio-astronomy (Hanbury-Brown, 1952)
- Early implementations
- Radiometry (Allred, 1962)
- Noise calibration (Spietz, 2003)
- Frequency noise (Vessot 1964)
- Phase noise (Walls 1976)
- Dual delay line system (Lance, 1982)
- Phase noise (Rubiola 2000 & 2002)
- Effect of amplitude noise (Rubiola, 2007)
- Frequency stability of a resonator (Rubiola)
- Dual-mixer time-domain instrument (Allan 1975, Stein 1983)
- Amplitude noise & laser RIN (Rubiola 2006)
- Noise of a power detector (Grop & Rubiola, in progress)
- Noise in chemical batteries (Walls 195)
- Semiconductors (Sampietro RSI 1999)
- Electromigration in thin films (Stoll 1989)
- Fundamental definition of temperature
- Hanbury Brown Twiss effect (Hanbury-Brown & Twiss 1956, Glattli 2004)

Cassiopeia A (or Cygnus A) radio source

Radio-astronomy

Measurement of the apparent angular size of stellar radio sources Jodrell Bank, Manchester



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Cygnus A (Harvard)

500 m² 500 m a few km R. Hanbury Brown & al., Nature 170(4338) \mathbb{R}_2 R, f = 125 MHzSquare law Square law B = 200 kHzdetector detector Band-pass Band-pass filter filter Radio Link Delay Correlator Y(ıf) e^{ιθ} X(ıf) X(If) Ē \overline{E}_{2}^{2} (PĘĒ,

wave planes

- The radio link breaks the hypothesis of symmetry of the two channels, introducing a phase $\boldsymbol{\theta}$
- The cross spectrum is complex
- The the antenna directivity results from the phase relationships
- The phase of the cross spectrum indicates the direction of the radio source

R. Hanbury Brown & al., Nature 170(4338) p.1061-1063, 20 Dec 1952 R. Hanbury Brown, R. Q. Twiss, Phyl. Mag. ser.7 no.366 p.663-682

Thermal noise compensation



hybrid output

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$$y_1(t) = \frac{1}{\sqrt{2}} x_2(t) + \frac{1}{\sqrt{2}} x_1(t)$$
$$y_2(t) = \frac{1}{\sqrt{2}} x_2(t) - \frac{1}{\sqrt{2}} x_1(t)$$

correlation

$$\begin{aligned} \mathcal{R}_{y_1 y_2}(\tau) &= \lim_{\theta \to \infty} \frac{1}{\theta} \int_{\theta} y_1(t) \, y_2^*(t-\tau) \, \mathrm{d}t \\ &= \frac{1}{2} \, \mathcal{R}_{x_2 x_2}(\tau) - \frac{1}{2} \, \mathcal{R}_{x_1 x_1}(\tau) \end{aligned}$$

Fourier transform and thermal noise

$$S_{y_1y_2}(f) = \frac{1}{2} S_{x_2}(f) - \frac{1}{2} S_{x_1}(f)$$
$$S_{y_1y_2}(f) = \frac{k_B(T_2 - T_1)}{2}$$

Radiometry & Johnson thermometry

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C. M. Allred, A precision noise spectral density comparator, J. Res. NBS 66C no.4 p.323-330, Oct-Dec 1962

Re-definition of the Kelvin?



Property of the Poisson process $\mu = \sigma^2$

Noise calibration

S = kT

thermal noise

shot noise $S = 2qI_{avg}R$

high accuracy of I_{avg} with a dc instrument

Compare shot and thermal noise with a noise bridge



This idea could turn into a redefinition of the temperature

Fig. 1. Theoretical plot of current spectral density of a tunnel junction (Eq. 3) as a function of dc bias voltage. The diagonal dashed lines indicate the shot noise limit, and the horizontal dashed line indicates the Johnson noise limit. The voltage span of the intersection of these limits is $4k_{\rm B}T/e$ and is indicated by vertical dashed lines. The bottom inset depicts the occupancies of the states in the electrodes in the equilibrium case, and the top inset depicts the out-of-equilibrium case where $eV \gg k_{\rm B}T$.

In a tunnel junction, theory predicts the amount of shot and thermal noise

L. Spietz & al., Primary electronic thermometry using the shot noise of a tunnel junction, Science 300(20) p. 1929-1932, jun 2003

Early implementations

1940-1950 technology



Spectral analysis at the single frequency f₀, in the bandwidth B Need a filter pair for each Fourier frequency

Measurement of the frequency noise of a H-maser



R. F. C. Vessot, Proc. Nasa Symp. on Short Term Frequency Stability p.111-118, Greenbelt, MD, 23-24 Nov 1964

Phase noise measurement



(relatively) large correlation bandwidth provides low noise floor in a reasonable time

F.L. Walls & al, Proc. 30th FCS pp.269-274, 1976 More popular after W. Walls, Proc. 46th FCS pp.257-261, 1992

Phase noise measurement



background noise



noise of a by-step attenuator



E. Rubiola, V. Giordano, Rev. Sci. Instrum. 71(8) p.3085-3091, aug 2000 E. Rubiola, V. Giordano, Rev. Sci. Instrum. 73(6) pp.2445-2457, jun 2002

E.Rubiola, V.Giordano,

Phase noise



Effect of amplitude noise

Should set both channels at the sweet point, if exists



The delay de-correlates the two inputs, so there is no sweet point





Should set both channels at the sweet point of the RF input, if exists, by offsetting the PLL or by biasing the IF



The effect of the AM noise is strongly reduced by the RF amplification

pink: noise rejected by correlation and averaging

E. Rubiola, R. Boudot, IEEE Transact. UFFC 54(5) pp.926-932, may 2007

Dual-delay-line method



Original idea: D. Halford's NBS notebook F10 p.19-38, apr 1975 37

First published: A. L. Lance & al, CPEM Digest, 1978

The delay line converts the frequency noise into phase noise

The high loss of the coaxial cable limits the maximum delay

Updated version: The optical fiber provides long delay with low attenuation (0.2 dB/km or 0.04 dB/µs)

A.L. Lance, W.D. Seal, F. Labaar ISA Transact.21 (4) p.37-84, Apr 1982

Optical version of the dual-delay-line method

Two completely separate systems measure the same oscillator under test



The only common part of the setup is the power splitter.

E. Salik, N. Yu, L. Maleki, E. Rubiola, Proc. Ultrasonics-FCS Joint Conf., Montreal, Aug 2004 p.303-306 Volyanskiy & al., JOSAB 25(12) 2140-2150, Dec.2008. Also arXiv:0807.3494v1 [physics.optics] July 2008

³⁹ Frequency stability of a resonator

Enrico's weird brain

- however, with the cryogenic sapphire oscillators we can do way better -



from cryogenic oscillator

- Bridge in equilibrium
 - The amplifier cannot flicker around ω_0 , which it does not know
- The fluctuation of the resonator natural frequency is estimated from phase noise
- Q matching prevents the master-oscillator noise from being taken in
- Correlation removes the noise of the instruments and the reference resonators

Amplitude noise & laser RIN

AM noise of RF/microwave sources



 In PM noise measurements, one can validate the instrument by feeding the same signal into the phase detector

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- In AM noise this is not possible without a lower-noise reference
- Provided the crosstalk was measured otherwise, correlation enables to validate the instrument





Laser RIN



AM noise of photonic RF/microwave sources



E. Rubiola, The measurement of AM noise, dec 2005 arXiv:physics/0512082v1 [physics.ins-det]

Measurement of the detector noise



Basic ideas

- Remove the noise of the source by balancing C–A and C–B
 - Use a lock-in amplifier to get a sharp null measurement
- Channels A and B are independent -> noise is averaged out
- Two separate JFET amplifiers are needed in the C channel
 - JFETs have virtually no bias-current noise
- Only the noise of the detector C remains

Noise in chemical batteries



-110 -120 -130 -140 s/sqrt(Hz) -150 -160 dbVrm -170 -180 -190 -200 -210 10 10000 100 1000 100000 Frequency (Hz)



- Do not waste DAC bits for a constant DC, $V = V_{B2}-V_{B1}$ has (almost) zero mean
- Two separate amplifiers measure the same quantity V
- Correlation rejects the amplifier nose, and the FFT noise as well



C. K. Boggs, A. D. Doak, F. L. Walls, Proc. IFCS p.367-373 1995

Noise in semiconductors



FIG. 2. Schematics of the building blocks of our correlation spectrum analyzer performing the suppression of the uncorrelated input noises by a digital processing of sampled data.





FIG. 9. Experimental frequency spectrum of the current noise from DUT resistances of 100 k Ω and 500 M Ω (continuous line) compared with the limits (dashed line) given by the instrument and set by residual correlated noise components.

FIG. 3. Schematics of the active test fixture for current noise measurements.

M. Sampietro & al, Rev. Sci. Instrum 70(5) p.2520-2525, may 1999

Electro-migration in thin films





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Fig. 1 1/f noise of an AlSi_{0.01}Cu_{0.002} thin film measured at room temperature (a) without and (b) with the phase-sensitive ac correlation technique. The Johnson noise level is indicated by the dashed line.



- Random noise: X' and X" (real and imag part) of a signal are statistically independent
- The detection on two orthogonal axes eliminates the amplifier noise.
 - This work with a single amplifier!
- The DUT noise is detected

$$S_{ud}(f) = \frac{1}{2} \left[S_{\alpha}(f) - S_{\varphi}(f) \right]$$

A. Seeger, H. Stoll, 1/f noise and defects in thin metal films, proc. ICNF p.162-167, Hong Kong 23-26 aug 1999 RF/microwave version: E. Rubiola, V. Giordano, H. Stoll, IEEE Transact. IM 52(1) pp.182-188, feb 2003

Hanbury Brown - Twiss effect

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in single-photon regime, anti-correlation shows up

R. Hanbury Brown, R. Q. Twiss, Correlation between photons in two coherent beams of light, Nature 177 (1956) 27-29

Also observed at microwave frequencies

C. Glattli & al. (2004), PRL 93(5) 056801, Jul 2004



 $kT = 2.7 \times 10^{-25} J at 20 mK$, $hv = 1.12 \times 10^{-24} J at 1.7 GHz$, kT/hv = -6.1 dB

Conclusions

- Rejection of the instrument noise
- AM noise, RIN, etc. -> validation of the instrument without a reference low-noise source
- Display quantities
 <Re{Syx}>m is faster and more accurate
 <Im{Syx}>m gives the background noise
 max{<Syx>m,0+} provide easier readout
- Applications in many fields of metrology

The cross spectrum method is magic Correlated noise sometimes makes magic difficult

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